



INFORMATION CITED BY APPLICANT THAT MAY BE MATERIAL TO THE
PROSECUTION OF THE SUBJECT APPLICATION

Applicant: M. Feldman Attorney Docket No. MEIP122467
Application No.: 10/814,755 Group Art Unit: 2877
Filed: March 31, 2004
Title: IMPROVED WAVELENGTH DETECTOR

U.S. PATENT DOCUMENTS

*Examiner Initials	Cite No.	Document No.	Kind Code	Date (mm/dd/yyyy)	Name
PC	U1	4,308,456	A	12/29/1981	Van Der Gaag et al.
PC	U2	5,627,648	A	05/06/1997	Garrett
PC	U3	5,729,347	A	03/17/1998	So
PC	U4	2002/0126288	A1	09/12/2002	Friberg et al.

FOREIGN PATENT DOCUMENTS

*Examiner Initial	Cite No.	Document No.	Kind Code	Publication Date (mm/dd/yyyy)	Country	English Abstract Provided	Translation Provided
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None

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner Initial	Cite No.
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None

Examiner	Date Considered
/Patrick Connolly/	(08/29/2006)

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SIL:vas